	TOTAL DOSE RADIATION TEST REPORT No. HM-MT-ITR-002	Issue 1 Rev.: Date: 16.03.92 Date: Page: 1/8
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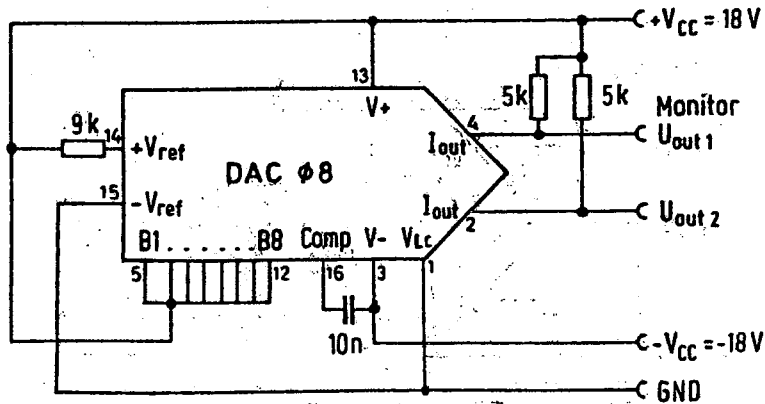
SCC Component No.: J38510/11302SEA		Component Designation: DAC-08AQ	Irradiation Spec. No.: TL/MTP/RP/001 Iss. 2A
Gen. Spec.: MIL-S-38510 H 5 Det. Spec.: M-M-38510/113 6 Amend.:		Evaluation: Acceptance Difussion: - Acceptance Lot: X	Project/Programme: MTP
Family: 08	Group: 04	Functional Assignment: D/A CONVERTER	Package: DIL-16
Manuf.Name: AD Address: Santa Clara (USA)		Irradiation Facility: H.M.I. Address: Berlin (GERMANY)	Test House: H.M.I. Address: Berlin (GERMANY)
Radiation Test Plan No.: RAD-MTP-HM-002 Iss. 1		Sample Size: 4 Irradiation Devices: 3 Control Devices: 1	Date Code: 8925 Mask No.: N/A
Radiation Source: Cobalt-60		Energy: 1,3 MeV Dose Rate: 10 Rad(Si)/s	Date of Test: 16.03.92

Electrical Measurements. Parameters Tested:

Nonlinearity (NL); Differential Nonlinearity (DNL); Gain Error (GE); Pos.Full Scale Voltage (VFS+); Neg.Full Scale Voltage (VFS-); Output Voltage at Bit Value N (VN); Pos.Zero Scale Current (IZS+); Neg.Zero Scale Current (IZS-); Pos.Full Scale Current (IFS+); Neg.Full Scale Current (IFS-); Logic Input Current Low Level (IlogL); Logic Input Current High Level (IlogH).

Irradiation Conditions: Biased: Y Unbiased: N Test Circuit: Figure 1	Irradiation Measurements Interval: Biased: N Unbiased: Y Test Circuit: N/A	Annealing Tests: YES Biased: Y Duration: 24 h. Unbiased: N Temp. °C: 25±3 Test Circuit: Figure 1
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Figure 1:



Irradiat. Respons.: H.M.I. Date: 16/03/92	Electr. Test Resp.: H.M.I. Date: 16/03/92
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Test Step	Description	Result or Actual Test Condition	Time In	Time Out	Exposure
1	Sample serialization	CONTROL R4, R1, R2, R3			
2	Initial Electrical Measurements	See 0 krad(Si) values in respective Parameter Data Tables	11:24	11:31	7 min.
3	Set-up of Test	Bias circuit verified according to Fig. 1			
4	Irradiation Exposure	Cumulative Dose: 15 krad(Si) Dose Rate: 10 rad(Si)/s Temperature: 25 °C	11:41	12:06	25 min.
5	Intermediate Electrical Measurements	See 15 krad(Si) values in respective Parameter Data Tables	12:10	12:16	6 min.
6	Set-up of Test	Bias circuit verified according to Fig. 1			
7	Irradiation Exposure	Cumulative Dose: 30 krad(Si) Dose Rate: 10 rad(Si)/s Temperature: 25 °C	13:05	13:30	25 min.
8	Intermediate Electrical Measurements	See 30 krad(Si) values in respective Parameter Data Tables	13:33	13:41	8 min.
9	Set-up of Test	Bias circuit verified according to Fig. 1			
10	Irradiation Exposure	Cumulative Dose: 45 krad(Si) Dose Rate: 10 rad(Si)/s Temperature: 25 °C	13:45	14:10	25 min.
11	Intermediate Electrical Measurements	See 45 krad(Si) values in respective Parameter Data Tables	14:16	14:23	7 min.
12	Annealing	Bias circuit verified according to Fig. 1. Temperature: 25 °C (average)	14:25 16/03	14:15 17/03	23h. 50 min.



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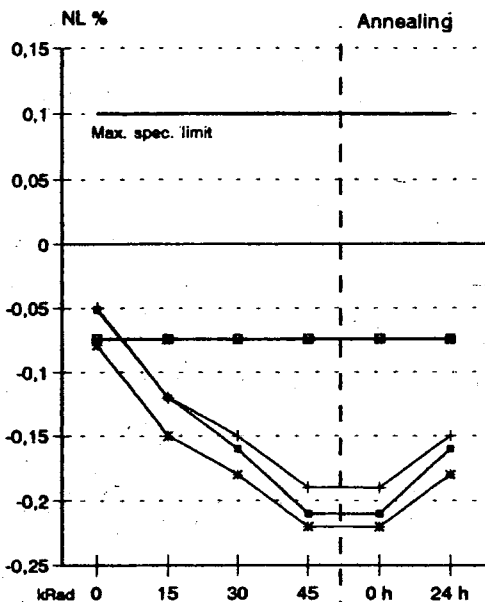
Test Step	Description	Result or Actual Test Condition	Time In	Time Out	Exposure
13	Electrical Measurements	See 24 h values in respective Parameter Data Tables	14:20	14:27	7 min.



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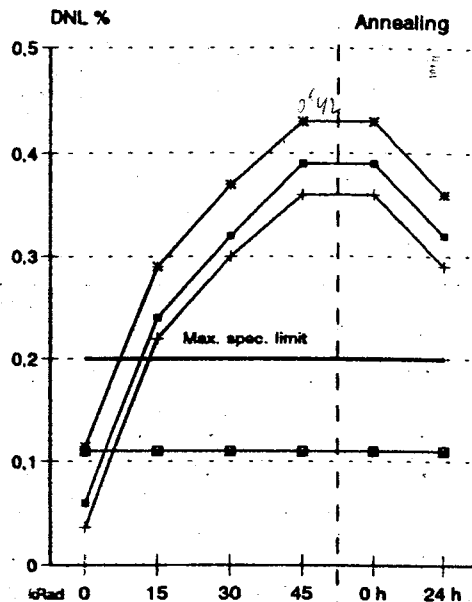
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**DAC 08
NONLINEARITY**



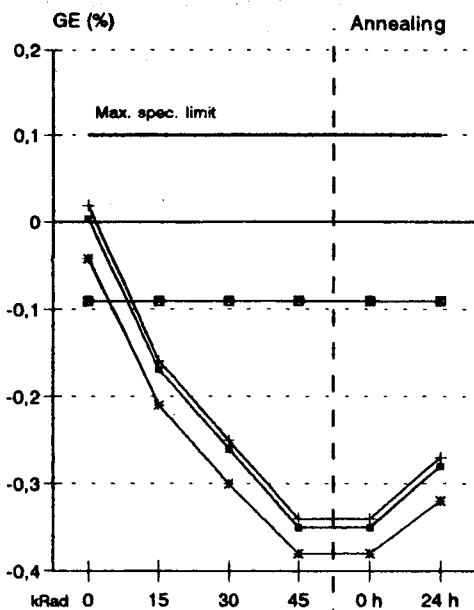
	kRad 0	15	30	45	0 h	24 h
CONTROL	-0,074	-0,074	-0,074	-0,074	-0,074	-0,074
R1	-0,05	-0,12	-0,15	-0,19	-0,19	-0,15
R2	-0,079	-0,15	-0,18	-0,22	-0,22	-0,18
R3	-0,051	-0,12	-0,16	-0,21	-0,21	-0,16

**DAC 08
DIFFERENTIAL NONLINEARITY**



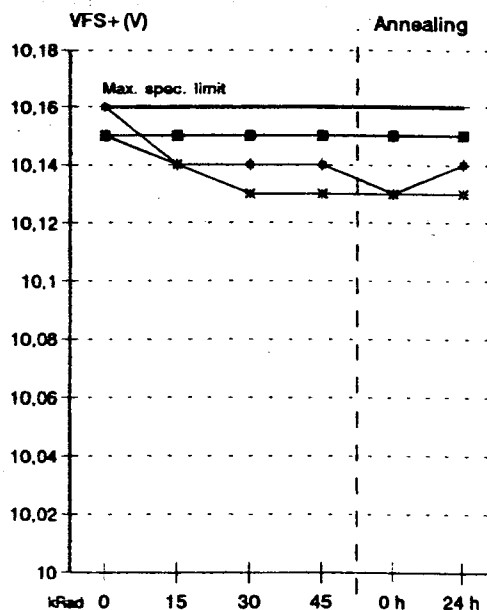
	kRad 0	15	30	45	0 h	24 h
CONTROL	0,11	0,11	0,11	0,11	0,11	0,11
R1	0,037	0,22	0,3	0,36	0,36	0,29
R2	0,114	0,29	0,37	0,43	0,43	0,36
R3	0,06	0,24	0,32	0,39	0,39	0,32

**DAC 08
GAIN ERROR**



	kRad 0	15	30	45	0 h	24 h
CONTROL	-0,091	-0,091	-0,091	-0,091	-0,091	-0,091
R1	0,019	-0,16	-0,25	-0,34	-0,34	-0,27
R2	-0,042	-0,21	-0,3	-0,38	-0,38	-0,32
R3	0,0037	-0,17	-0,26	-0,35	-0,35	-0,28

**DAC 08
POS. FULL SCALE VOLTAGE**



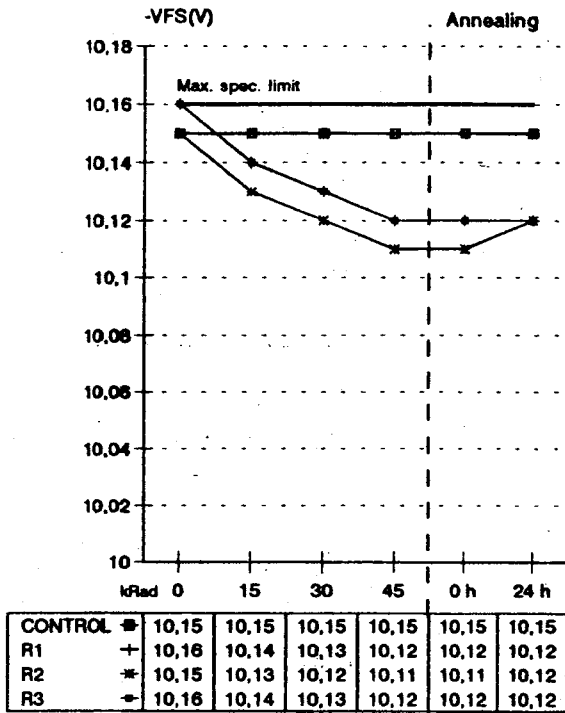
	kRad 0	15	30	45	0 h	24 h
CONTROL	10,15	10,15	10,15	10,15	10,15	10,15
R1	10,16	10,14	10,14	10,14	10,13	10,14
R2	10,15	10,14	10,13	10,13	10,13	10,13
R3	10,16	10,14	10,14	10,14	10,13	10,14



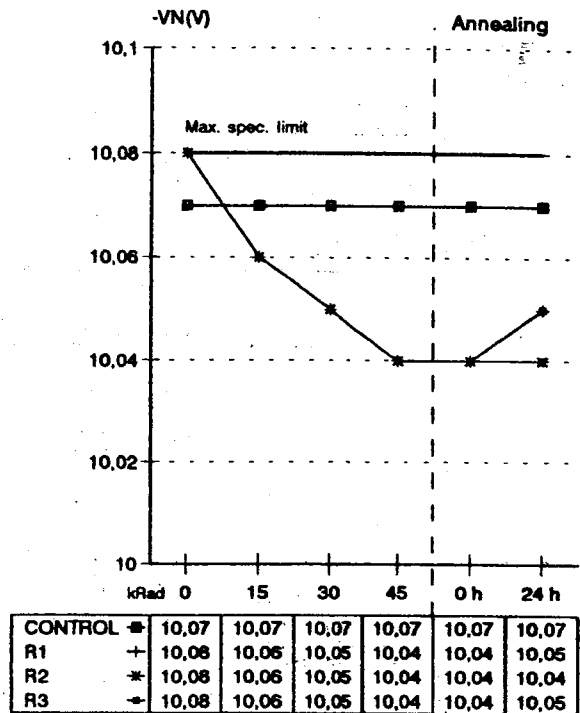
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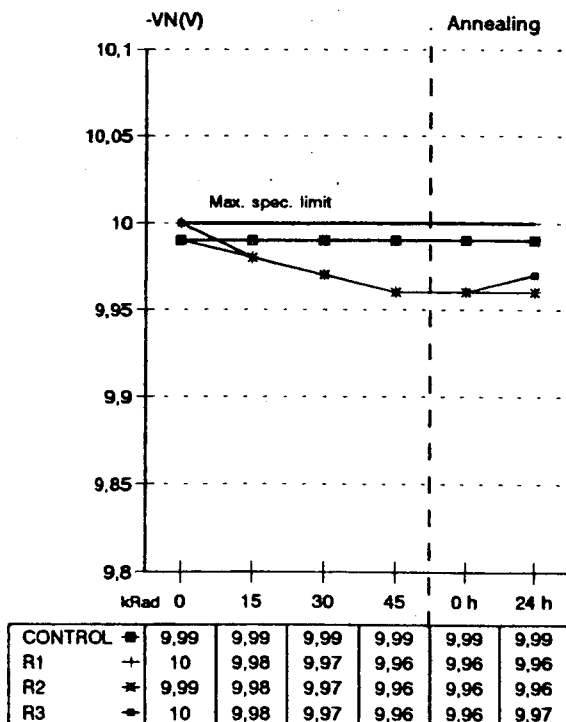
**DAC 08
NEG. FULL SCALE VOLTAGE**



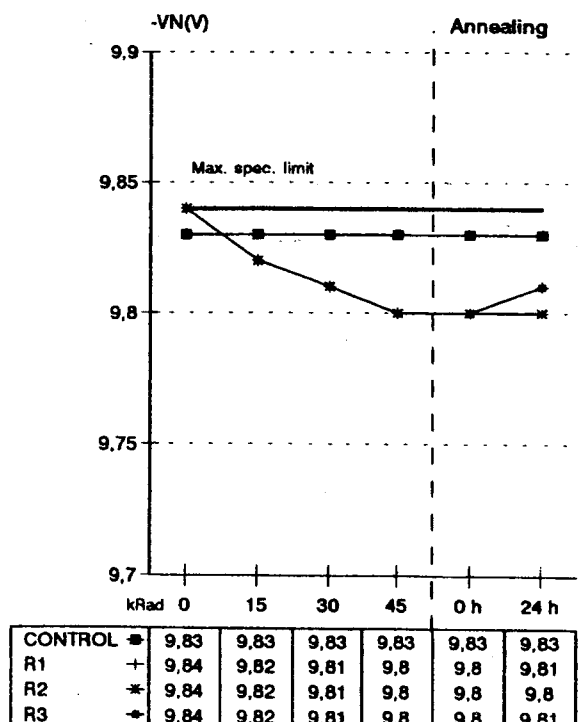
**DAC 08
OUTPUT VOLTAGE AT BIT-VALUE 1**



**DAC 08
OUTPUT VOLTAGE AT BIT-VALUE 2**



**DAC 08
OUTPUT VOLTAGE AT BIT-VALUE 4**

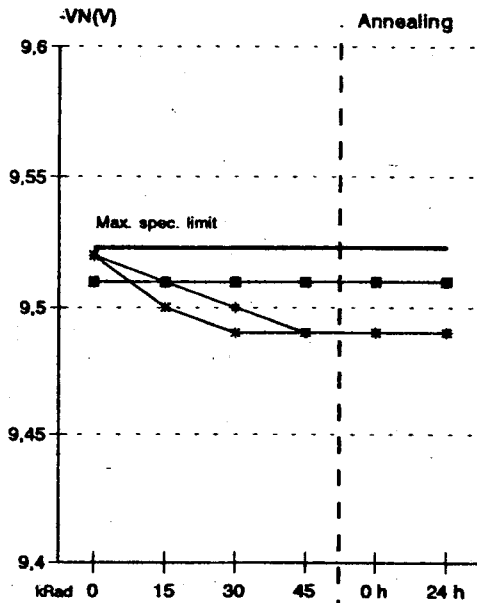




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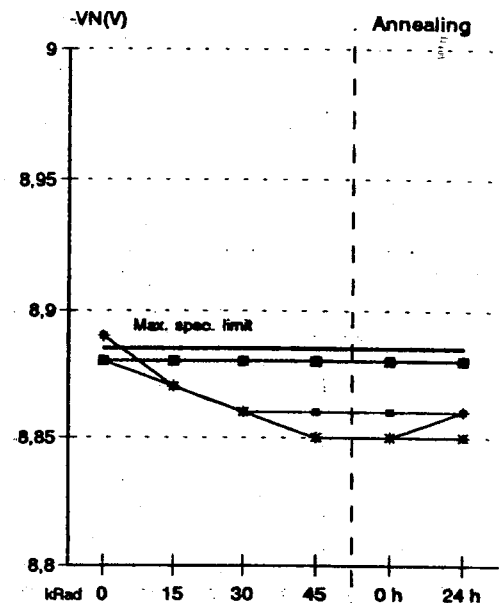
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**DAC 08
OUTPUT VOLTAGE AT BIT-VALUE 8**



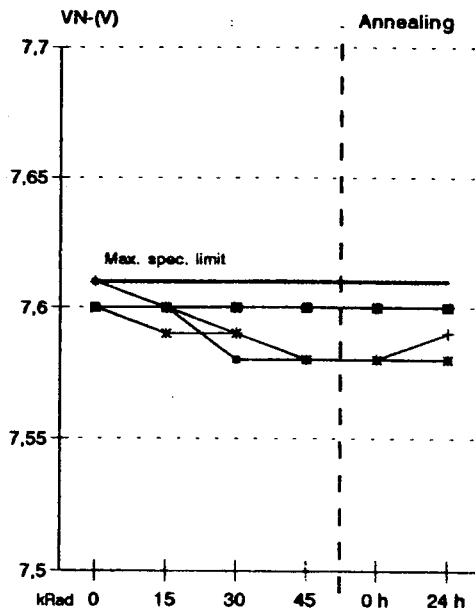
	kRad	0	15	30	45	0 h	24 h
CONTROL	■	9,51	9,51	9,51	9,51	9,51	9,51
R1	+	9,52	9,51	9,5	9,49	9,49	9,49
R2	*	9,52	9,5	9,49	9,49	9,49	9,49
R3	◄	9,52	9,51	9,5	9,49	9,49	9,49

**DAC 08
OUTPUT VOLTAGE AT BIT-VALUE 16**



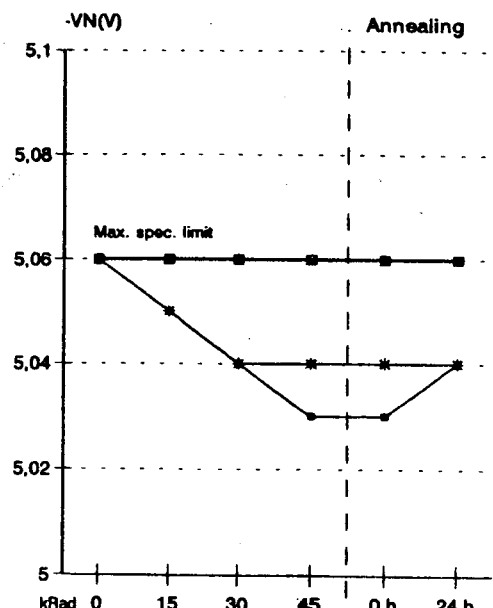
	kRad	0	15	30	45	0 h	24 h
CONTROL	■	8,88	8,88	8,88	8,88	8,88	8,88
R1	+	8,89	8,87	8,86	8,85	8,85	8,86
R2	*	8,88	8,87	8,86	8,85	8,85	8,85
R3	◄	8,89	8,87	8,86	8,86	8,86	8,86

**DAC 08
OUTPUT VOLTAGE AT BIT-VALUE 32**



	kRad	0	15	30	45	0 h	24 h
CONTROL	■	7,6	7,6	7,6	7,6	7,6	7,6
R1	+	7,61	7,6	7,59	7,58	7,58	7,59
R2	*	7,6	7,59	7,59	7,58	7,58	7,58
R3	◄	7,61	7,6	7,58	7,58	7,58	7,58

**DAC 08
OUTPUT VOLTAGE AT BIT-VALUE 64**



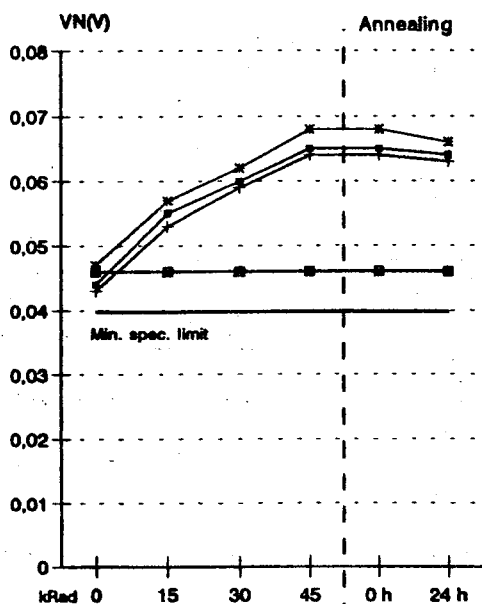
	kRad	0	15	30	45	0 h	24 h
CONTROL	■	5,06	5,06	5,06	5,06	5,06	5,06
R1	+	5,06	5,05	5,04	5,04	5,04	5,04
R2	*	5,06	5,05	5,04	5,04	5,04	5,04
R3	◄	5,06	5,05	5,04	5,03	5,03	5,04



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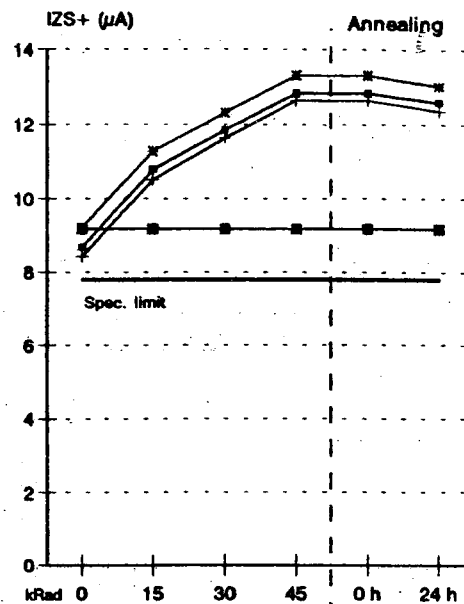
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**DAC 08
OUTPUT VOLTAGE AT BIT-VALUE 128**



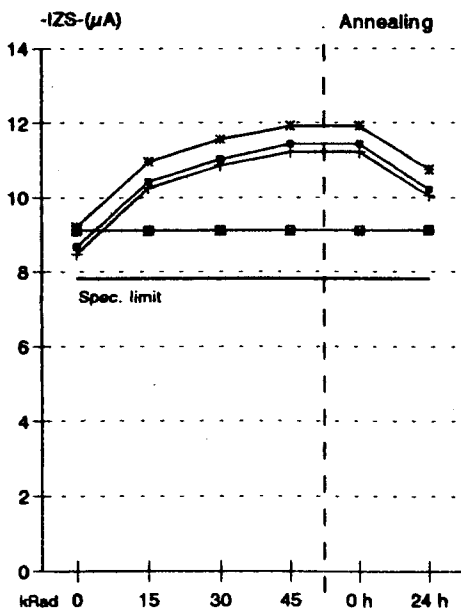
CONTROL	→	0,046	0,048	0,046	0,046	0,046	0,046
R1	+	0,043	0,053	0,059	0,064	0,064	0,063
R2	*	0,047	0,057	0,062	0,068	0,068	0,066
R3	→	0,044	0,055	0,06	0,065	0,065	0,064

**DAC 08
POS. ZERO SCALE CURRENT**



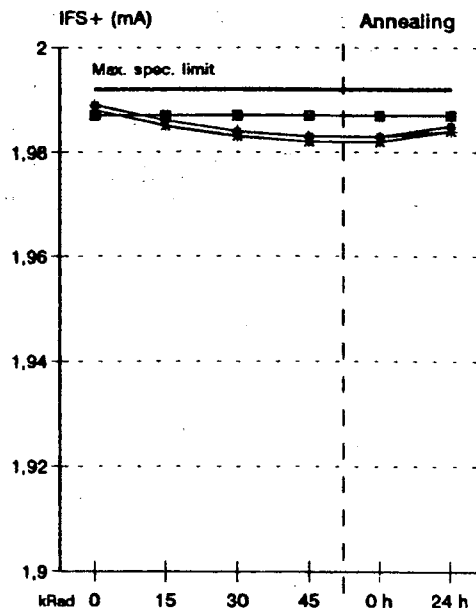
CONTROL	→	9,18	9,18	9,18	9,18	9,18	9,18
R1	+	8,43	10,52	11,63	12,64	12,64	12,36
R2	*	9,23	11,28	12,32	13,32	13,32	13,03
R3	→	8,68	10,79	11,85	12,84	12,84	12,59

**DAC 08
NEG. ZERO SCALE CURRENT**



CONTROL	→	9,112	9,109	9,109	9,109	9,109	9,115
R1	+	8,465	10,26	10,86	11,22	11,22	10,05
R2	*	9,209	10,96	11,56	11,92	11,92	10,76
R3	→	8,658	10,43	11,03	11,44	11,44	10,23

**DAC 08
POS. FULL SCALE CURRENT**



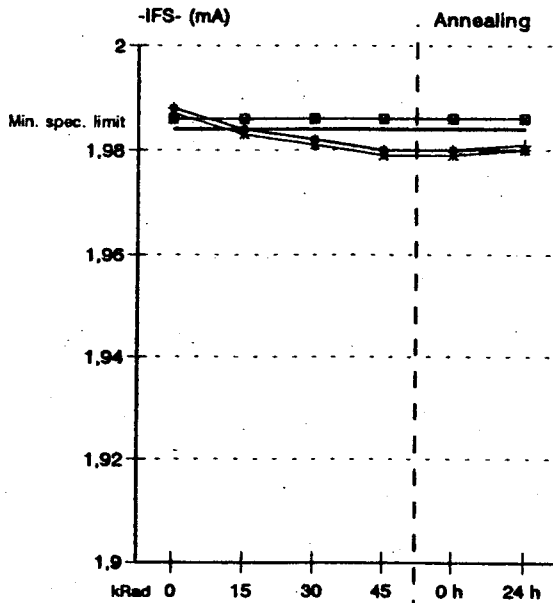
CONTROL	→	1,987	1,987	1,987	1,987	1,987	1,987
R1	+	1,989	1,986	1,984	1,983	1,983	1,984
R2	*	1,988	1,985	1,983	1,982	1,982	1,984
R3	→	1,989	1,986	1,984	1,983	1,983	1,985



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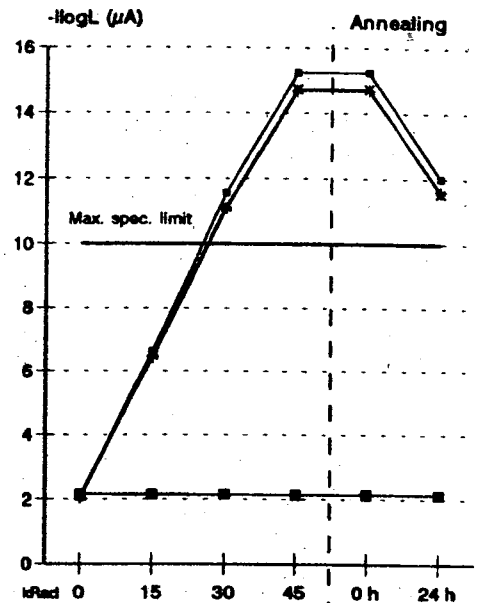
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**DAC 08
NEG. FULL SCALE CURRENT**



CONTROL	→	1,986	1,986	1,986	1,986	1,986	1,986
R1	+	1,988	1,984	1,982	1,98	1,98	1,981
R2	*	1,987	1,983	1,981	1,979	1,979	1,98
R3	←	1,988	1,984	1,982	1,98	1,98	1,98

**DAC 08
LOGIC INPUT CURRENT LOW LEVEL**



CONTROL	→	2,157	2,147	2,144	2,14	2,14	2,135
R1	+	2,052	6,438	11,1	14,68	14,68	11,62
R2	*	2,104	6,493	11,14	14,73	14,73	11,58
R3	←	2,05	6,64	11,57	15,24	15,24	12,02

**DAC 08
LOGIC INPUT CURRENT HIGH LEVEL**

Max. spec. limit 10µA



CONTROL	→	0,056	0,056	0,061	0,059	0,059	0,06
R1	+	0,057	0,478	0,921	1,265	1,265	0,715
R2	*	0,057	0,461	0,962	1,338	1,338	0,74
R3	←	0,056	0,455	0,933	1,339	1,339	0,76